

Qualification Results Summary for ADM3260 Die Revision and MSL Rating Change

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	3 x 77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	3 x 77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3 x 77	Pass
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	1 x 77	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	1 x 30	Pass
Latch-Up	JEDEC JESD78	1 x 3	Pass ±100mA @ +8.25V
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC JS-001	3/voltage	Pass ±3000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC JESD22-C101	3/voltage	Pass ±1250V

*Preconditioned per JEDEC/IPC J-STD-020